

July 2006

FDD8580/FDU8580

N-Channel PowerTrench® MOSFET

20V, **35A**, **9**mΩ

Features

- Max $r_{DS(on)} = 9m\Omega$ at $V_{GS} = 10V$, $I_D = 35A$
- Max $r_{DS(on)} = 13m\Omega$ at $V_{GS} = 4.5V$, $I_D = 33A$
- Low gate charge: $Q_{g(TOT)} = 19nC(Typ)$, $V_{GS} = 10V$
- Low gate resistance
- 100% Avalanche tested
- RoHS compliant

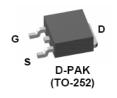


General Description

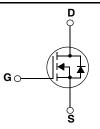
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{\text{DS}(\text{on})}$ and fast switching speed.

Application

- Vcore DC-DC for Desktop Computers and Servers
- VRM for Intermediate Bus Architecture







MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V_{DS}	Drain to Source Voltage		20	V
V_{GS}	Gate to Source Voltage		±20	V
	Drain Current -Continuous (Package Limited)		35	
I _D	-Continuous (Die Limited)		58	Α
	-Pulsed	(Note 1)	159	
E _{AS}	Single Pulse Avalanche Energy	(Note 2)	66	mJ
P_{D}	Power Dissipation		49.5	W
T _J , T _{STG}	Operating and Storage Temperature		-55 to 175	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case TO-252,TO-251	3.03	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient TO-252,TO-251	100	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient TO-252,1in ² copper pad area	52	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD8580	FDD8580	TO-252AA	13"	12mm	2500 units
FDU8580	FDU8580	TO-251AA	N/A(Tube)	N/A	75 units

Electrical Characteristics T_J = 25°C unless otherwise noted

Symbol	Parameter	lest Conditions	Wiin	тур	wax	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	20			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25°C		17.3		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 16V, V _{GS} = 0V			1 250	μА
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20V			±100	nA

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1.2	1.8	2.5	V
<u> </u>		I_D = 250 μ A, referenced to 25°C		-6.3		mV/°C
	Drain to Source On Resistance	V _{GS} = 10V, I _D = 35A		6.6	9.0	
r _{DO(})		$V_{GS} = 4.5V, I_D = 33A$		9.3	13.0	mΩ
'DS(on)		$V_{GS} = 10V, I_D = 35A$ $T_J = 175^{\circ}C$		10.6	14.5	11132
9 _{FS}	Forward Transcondductance	$V_{DS} = 5V, I_{D} = 35A$		61		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V - 40V V - 0V	1085	1445	pF
C _{oss}	Output Capacitance	V _{DS} = 10V, V _{GS} = 0V, f = 1MHz	340	450	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11/11/12	205	310	pF
R_g	Gate Resistance	f = 1MHz	1.3		Ω

Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time	.,,	7	14	ns
t _r	Rise Time	V_{DD} = 10V, I_{D} = 35A V_{GS} = 10V, R_{GS} = 27 Ω	11	20	ns
$t_{d(off)}$	Turn-Off Delay Time	$V_{GS} = 10V, R_{GS} = 27\Omega$	59	94	ns
t _f	Fall Time		34	54	ns
$Q_{g(TOT)}$	Total Gate Charge at 10V	V _{GS} = 0V to 10V	19	27	nC
$Q_{g(5)}$	Total Gate Charge at 5V	$V_{GS} = 0V \text{ to } 5V$ $V_{DD} = 10V$ $I_{D} = 35A$	10	14	nC
Q_{gs}	Gate to Source Gate Charge	$I_{0} = 35A$ $I_{0} = 1.0 \text{mA}$	3.5		nC
Q_{gd}	Gate to Drain "Miller" Charge		3.9		nC

Drain-Source Diode Characteristics

,	\/	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 35A$	0.95	1.25	\/
	v _{SD}	Source to Drain Diode 1 of Ward Voltage	V _{GS} = 0V, I _S = 15A	0.85	1.2	'
ŀ	t _{rr}	Reverse Recovery Time	$I_F = 35A$, di/dt = 100A/ μ s	26	39	ns
	Q _{rr}	Reverse Recovery Charge	$I_F = 35A$, di/dt = 100A/ μ s	19	29	nC

1: Pulse time < 300 µs, Duty cycle = 2%. 2: Starting T_J = 25°C, L = 0.3mH, I_{AS} = 21A, V_{DD} = 18V, V_{GS} = 10V.



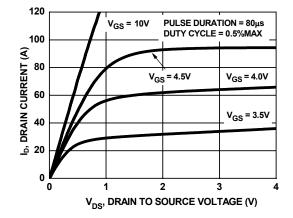


Figure 1. On Region Characteristics

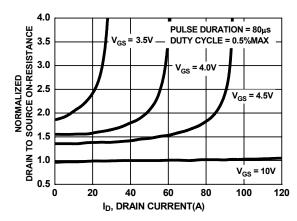


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

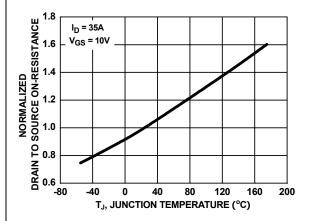


Figure 3. Normalized On Resistance vs Junction Temperature

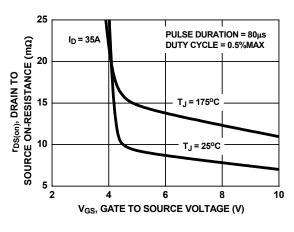


Figure 4. On-Resistance vs Gate to Source Voltage

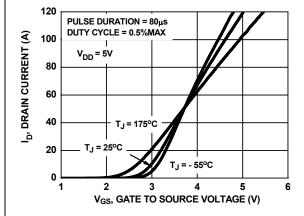


Figure 5. Transfer Characteristics

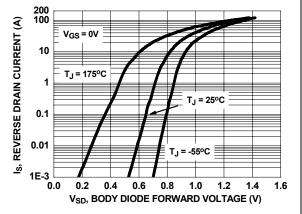
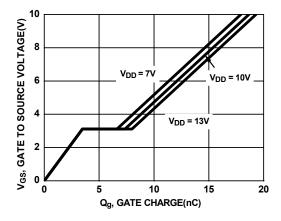


Figure 6. Source to Drain Diode Forward Voltage vs Source Current





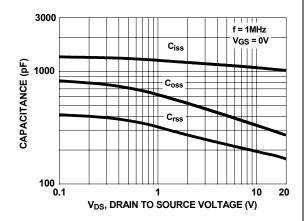
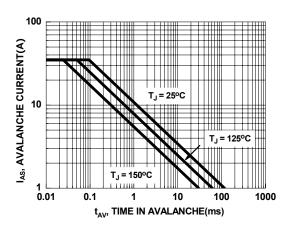


Figure 7. Gate Charge Characteristics

Figure 8. Capacitance vs Drain to Source Voltage



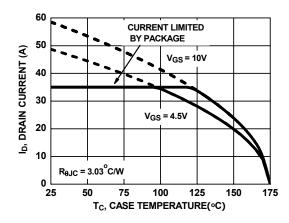
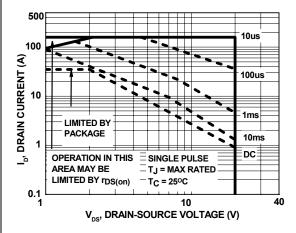


Figure 9. Unclamped Inductive Switching Capability

Figure 10. Maximum Continuous Drain Current vs Case Temperature



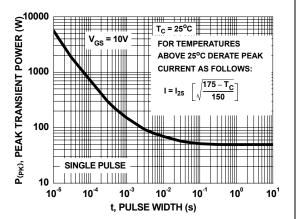


Figure 11. Forward Bias Safe Operating Area

Figure 12. Single Pulse Maximum Power Dissipation

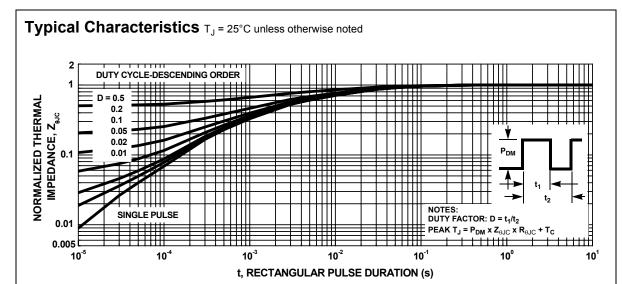


Figure 13. Transient Thermal Response Curve

UniFET™ $\mathsf{UltraFET}^{\circledR}$ VCX^{TM} Wire™

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